

Contract Service for Crystal Growth

Material Solutions for Your Innovative R&D

Versatile Kinds of Growth Methods in House

FZ (Floating Zone)	<ul style="list-style-type: none">➤ Low cost and high purity by crucible free growth➤ Capable of:<ul style="list-style-type: none">➤ Atmosphere control➤ Very high temperature; >3000deg.C
CZ (Czochralski)	<ul style="list-style-type: none">➤ Simple structure allowing for large crystals; >100mm dia.➤ Automatic diameter control of crystal growth
VB (Vertical Bridgeman)	<ul style="list-style-type: none">➤ Highly reproducible➤ Low cost
TSSG/KY (Top Seeded Solution Growth) (Kyropoulos)	<ul style="list-style-type: none">➤ Low stress by small temperature gradient
DCCZ (Double Crucible CZ)	<ul style="list-style-type: none">➤ High homogeneity for wide range solid solution from incongruent melt and doping concentration
EFG (Edge-Defined Film-Fed Growth)	<ul style="list-style-type: none">➤ Arbitrary shape of cross section➤ High homogeneity for wide range solid solution from incongruent melt and doping concentration in die



FZ



CZ



DCCZ



KY



VB

OXIDE

OXIDE Corporation

1747-1 Maginohara, Mukawa, Hokuto, Yamanashi 408-0302 JAPAN
Tel: +81-551-26-0022, Fax: +81-551-26-0033



✉ sales@opt-oxide.com

🖥️ <https://www.opt-oxide.com>

✕ Oxide Yamanashi

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Practical Experience

Mg:SLT/Mg:SLN, SLT/SLN, CLBO, BBO, LBO, KT, TeO₂, LBGO, LGT, TGG, TSAG, YIG, YAG, YSO, Nd:YVO₄, GdVO₄, GSO, LGSO, GPS, BSO, SrI₂, Mg₂SiO₄, TiO₂, LiB₃O₅, Li₂B₄O₇, Sapphire, LiCAF etc.

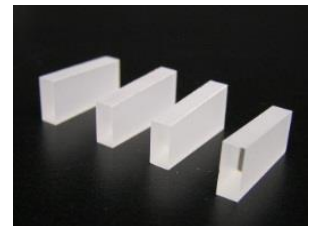


SLT (Stoichiometric LiTaO₃)

Facilities

➤ Crystal Processing

Wafer Slicer, OD Cutter, Automatic Dicing Saw, Cylindrical Grinder, Surface Grinder, Lapping & Polishing Machine



➤ Measurement and Evaluation

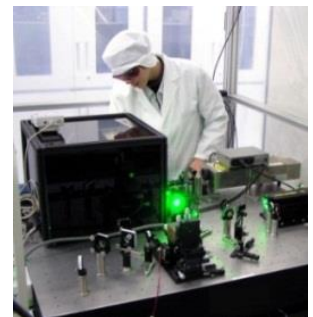
1. Single Crystals

Spectrophotometer, Differential Scanning Calorimeter, Polarization Microscope, X-ray Laue Camera, X-ray Diffractometer, X-ray Topography, Schlieren Optical System, Zygo Interferometer, Refractometer



2. Optical Devices

Life-time Testing System, Optical Loss Measurement, Photo-Thermal Common Path Interferometer



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